

Solid State Direct Drive RF Linac: Control System

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SIEMENS

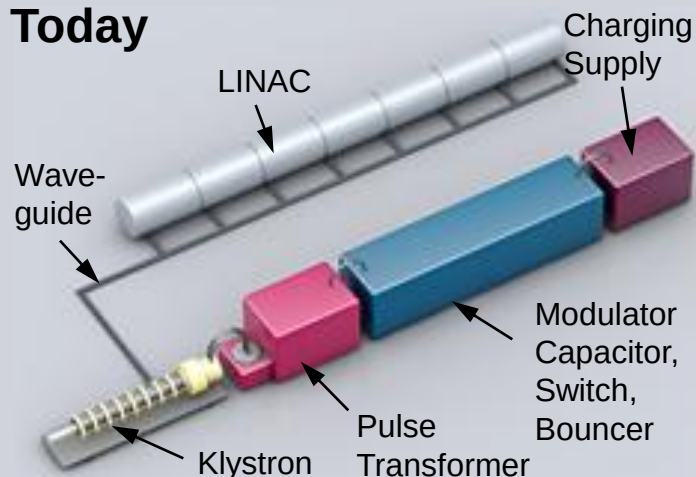
Overview

- Motivation
- RF Module Concept
- Control System Context
- Control System for Power Injection Tests
- Digital Control System
- Results
- Summary and Outlook

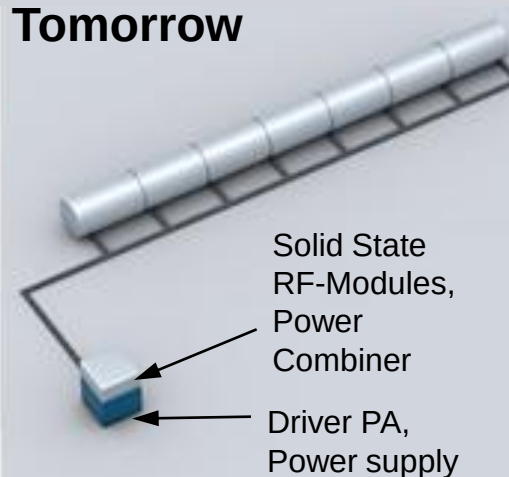
Motivation

- Electromagnetically coupled resonating cavities of traditional LINACs are driven by a single (or few) external RF power source connected via a waveguide and power couplers.
- Traditional RF power sources (e.g. Klystrons) can be replaced by high power SiC solid state RF-modules to enable compact system designs.
- Two implementation phases are planned

Today



Tomorrow

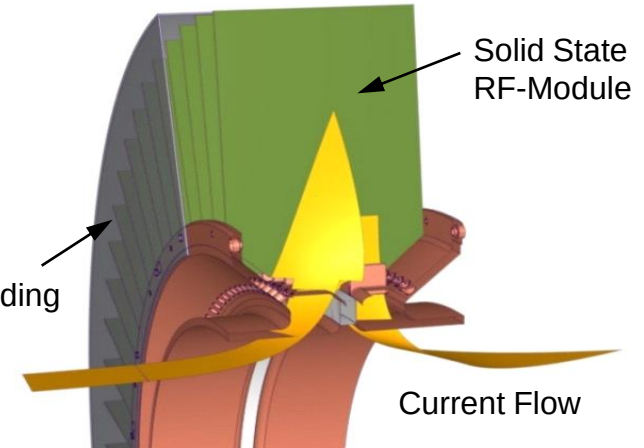
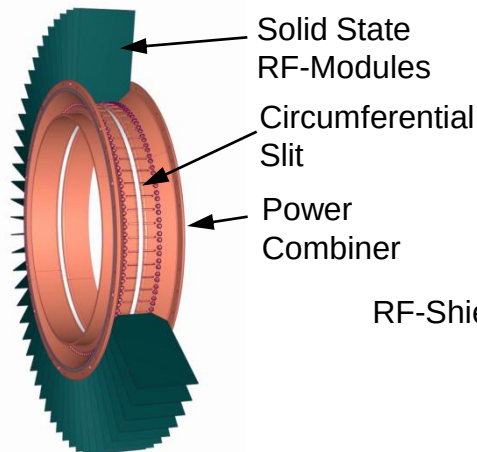
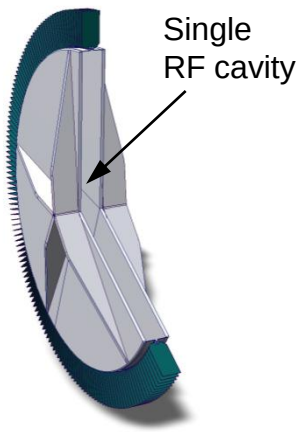


Future



Benefit of Solid State Direct Drive Concept

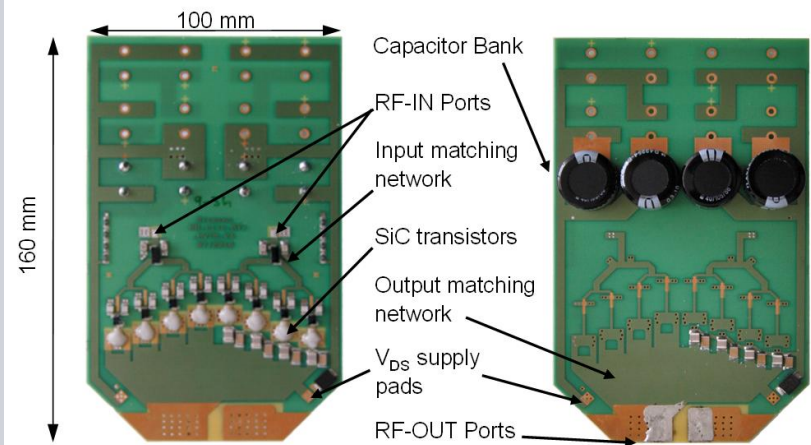
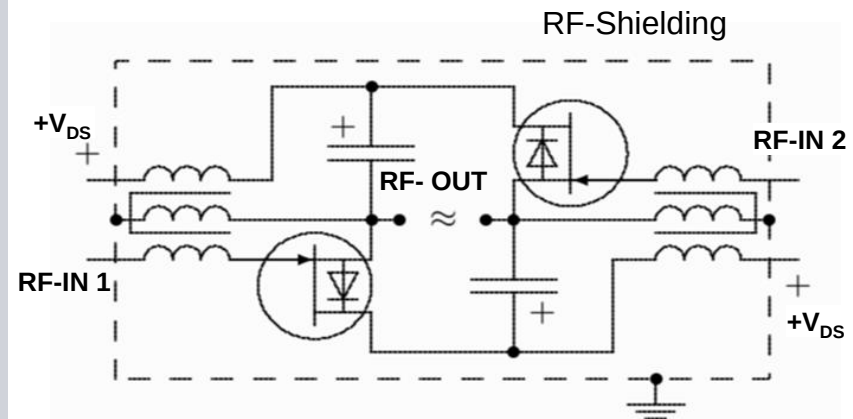
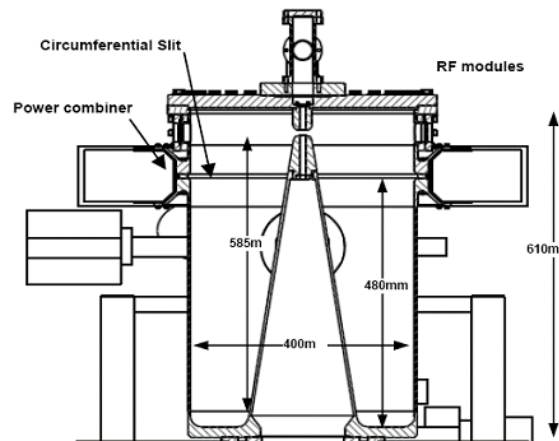
- Distributed RF-source for each cavity → better reliability, better maintenance
- Simple scalable power levels → lower cost, better maintenance
- Independent phase and power control in each cavity → higher flexibility
- No external RF-source, waveguide or mode couplers → lower cost, low footprint
- High efficiency of RF-Modules → lower operation cost



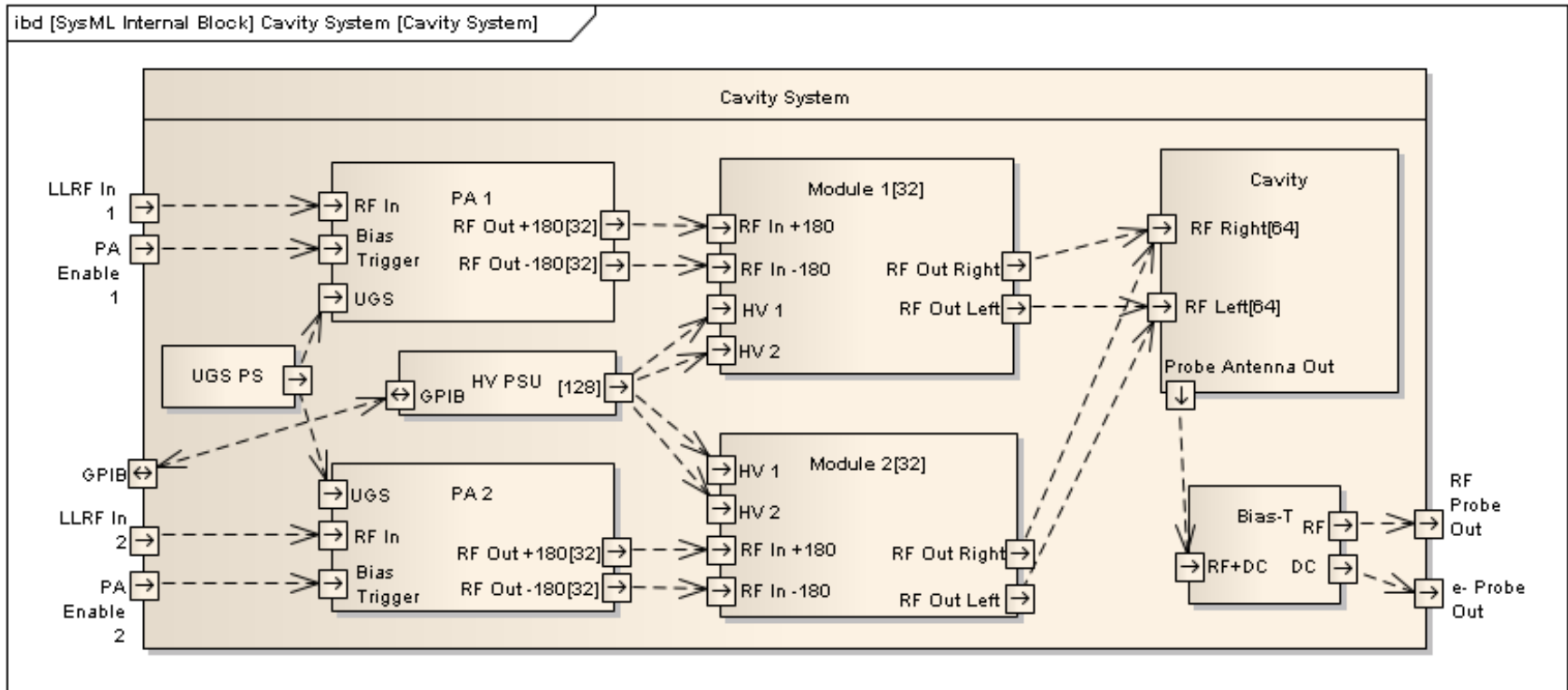
Solid State Direct Drive RF-Module

- Parallel push-pull topology (circlotron)
- 2-layer FR4 board
- 8 SiC transistors per RF-module

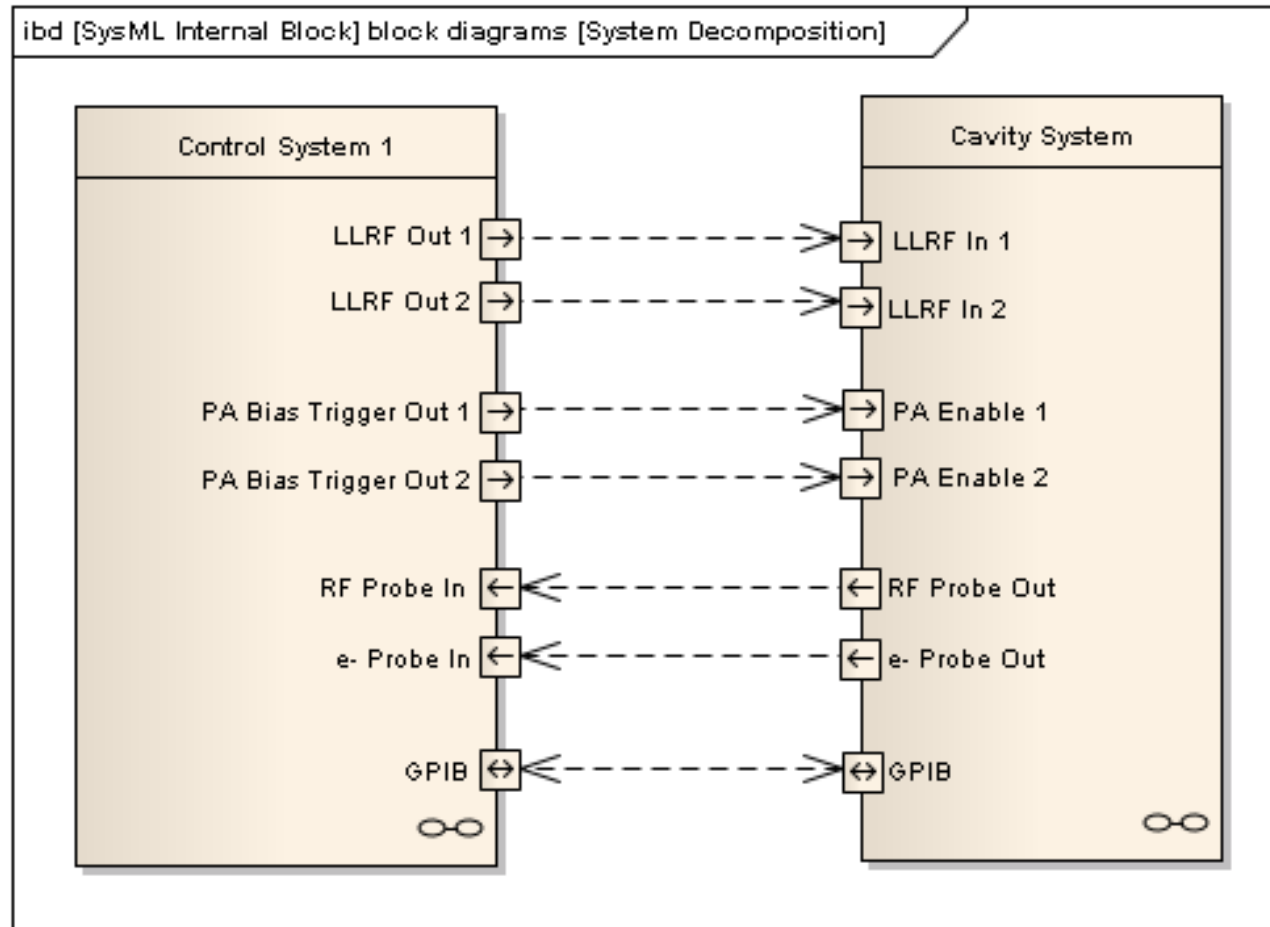
See Irsigler R. et al, 3B-9, PPC11, Chicago IL, USA



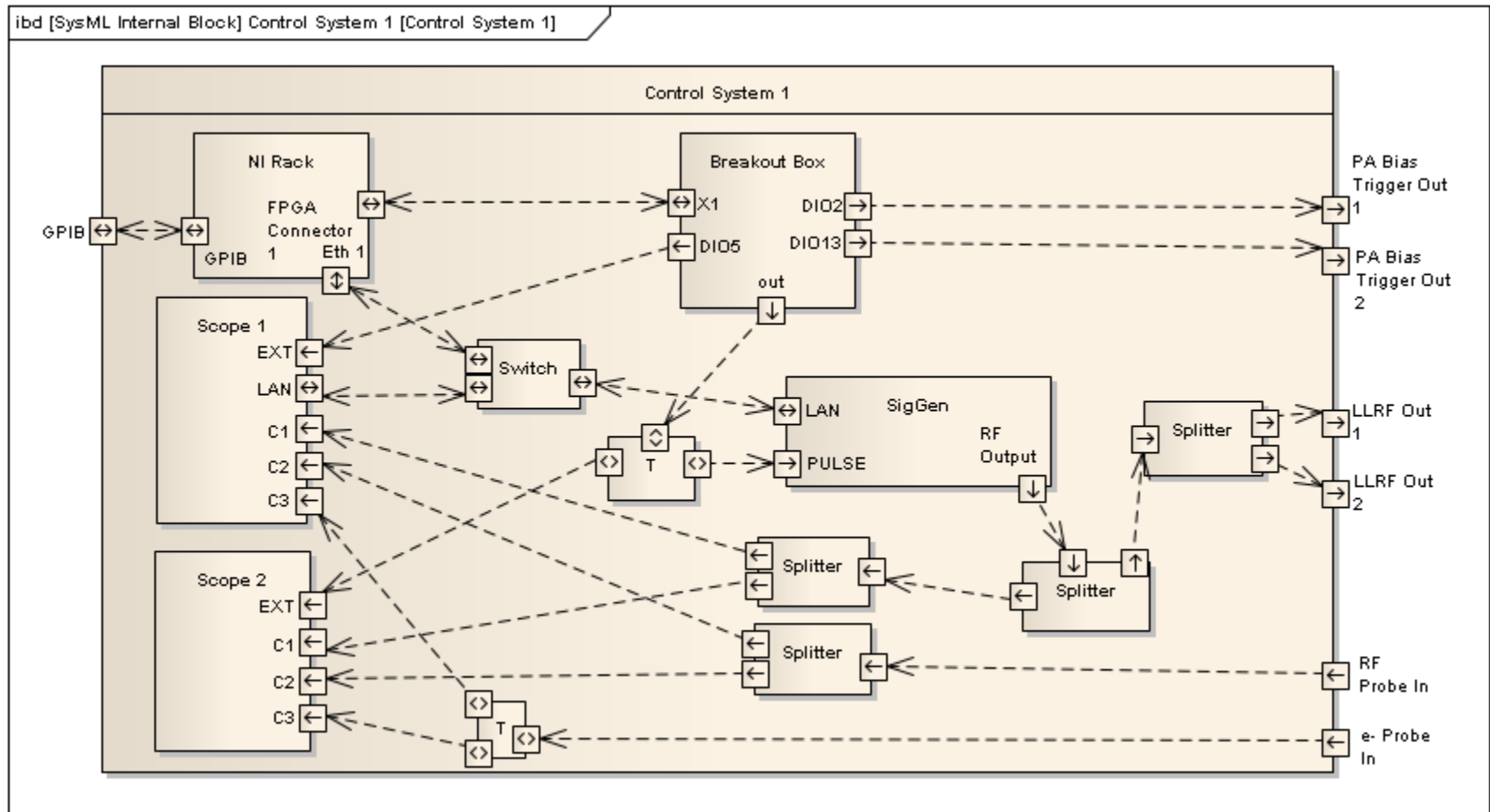
Cavity (Sub-)System



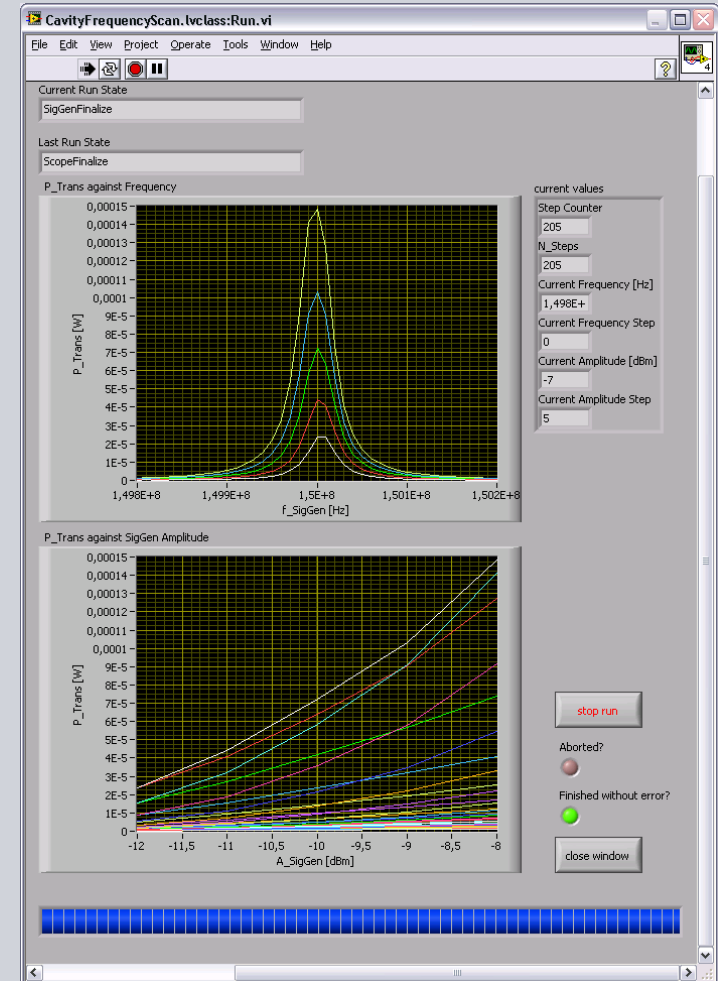
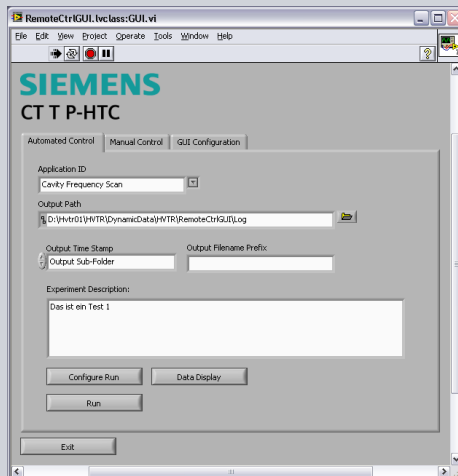
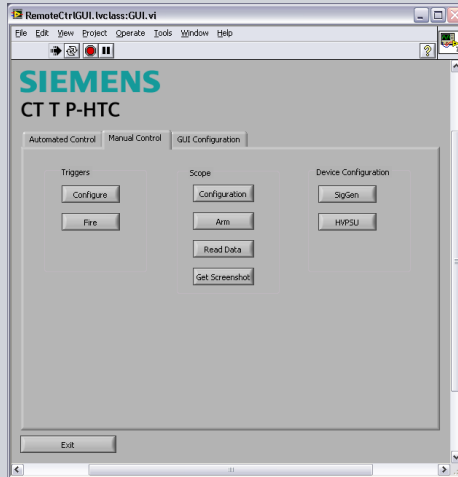
System Decomposition



Control (Sub-)System for Power Injection Tests

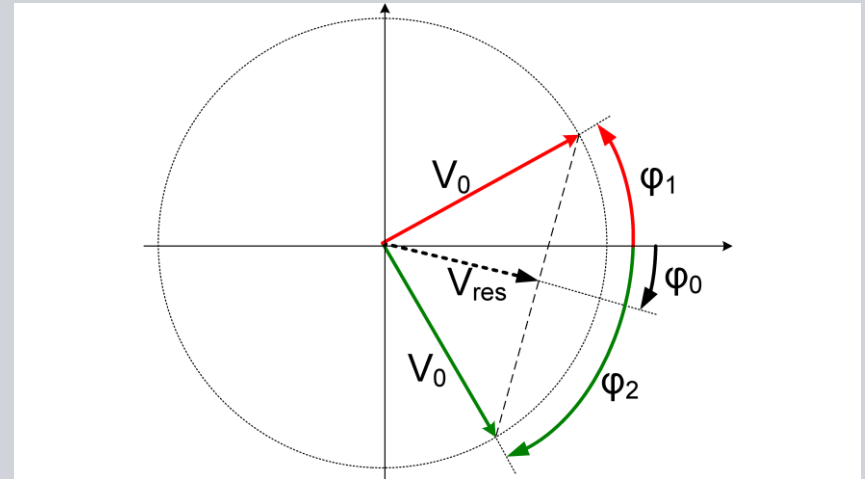


Control Software



Outphasing for E-Field Amplitude Control

- RF modules are nonlinear and time variant devices:
- SiC transistors heat up
- Capacitors discharge
- RF modules have maximum efficiency at maximum output power
- Cavity slot acts as a power combiner
- Two groups of modules with independent LLRF signals



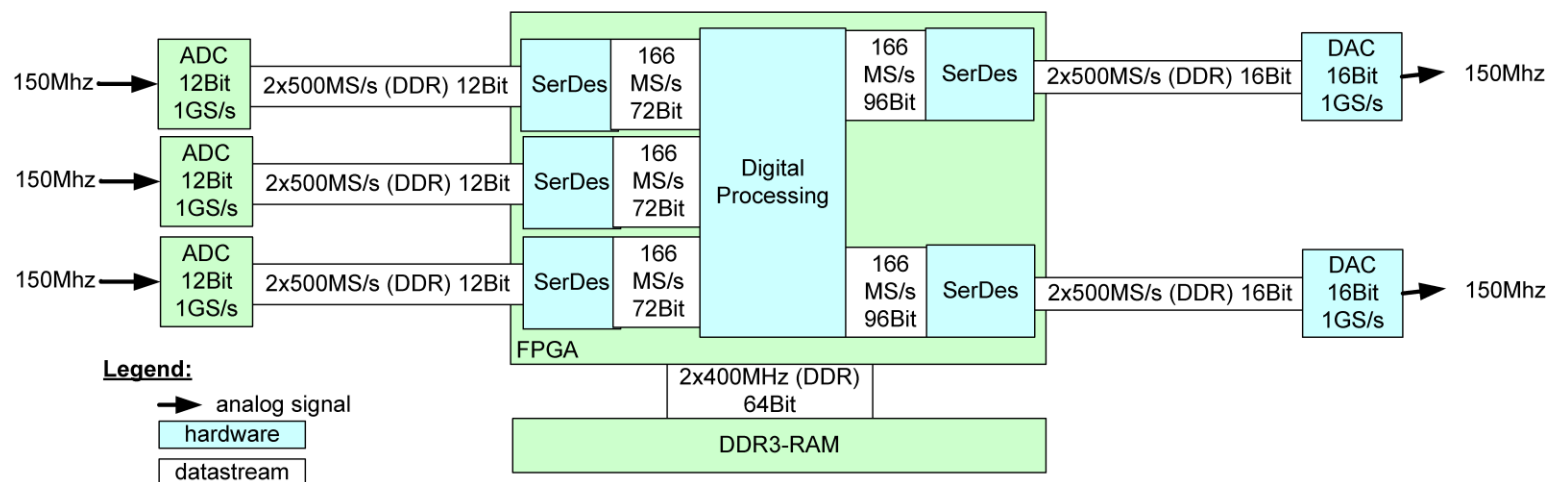
$$V_{res} = V_0 \cos \left(\frac{\varphi_1 - \varphi_2}{2} \right)$$

$$\varphi_0 = \frac{\varphi_1 + \varphi_2}{2}$$

SCCRT (Subsystem Cavity Controller Real Time) Design Goals

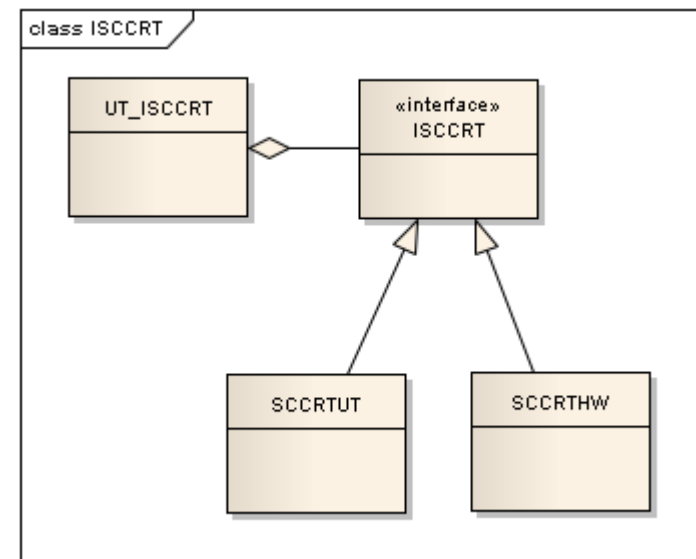
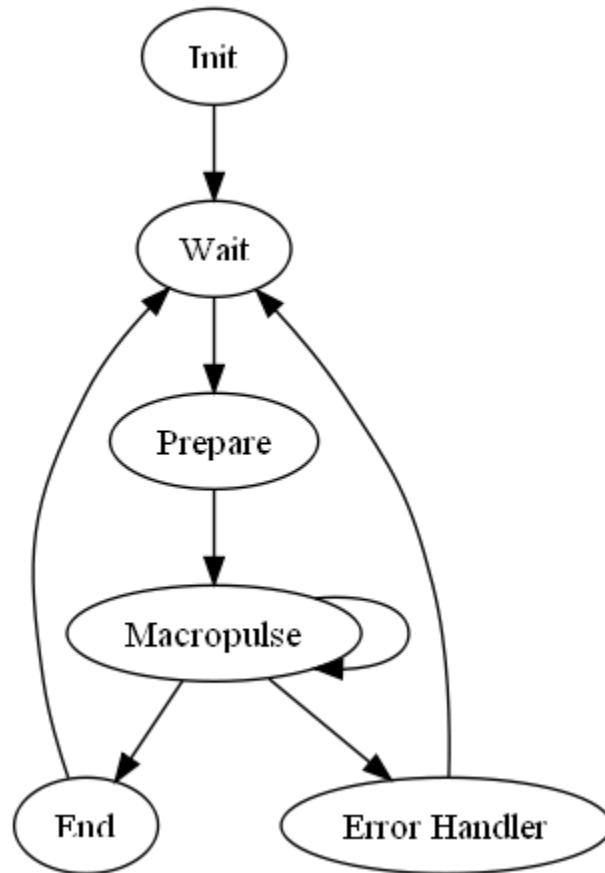
- 1GHz sampling rate for ADCs and DACs
- 3x 16bit ADC
- 2x 12bit DAC
- 10 input triggers (1ns resolution)
- 10 output triggers (1ns resolution)
- 166MHz 6-to-1 res 1-to-6 SerDes

See Sirtl J. et al, MOPC152, IPAC11,
San Sebastian, Spain



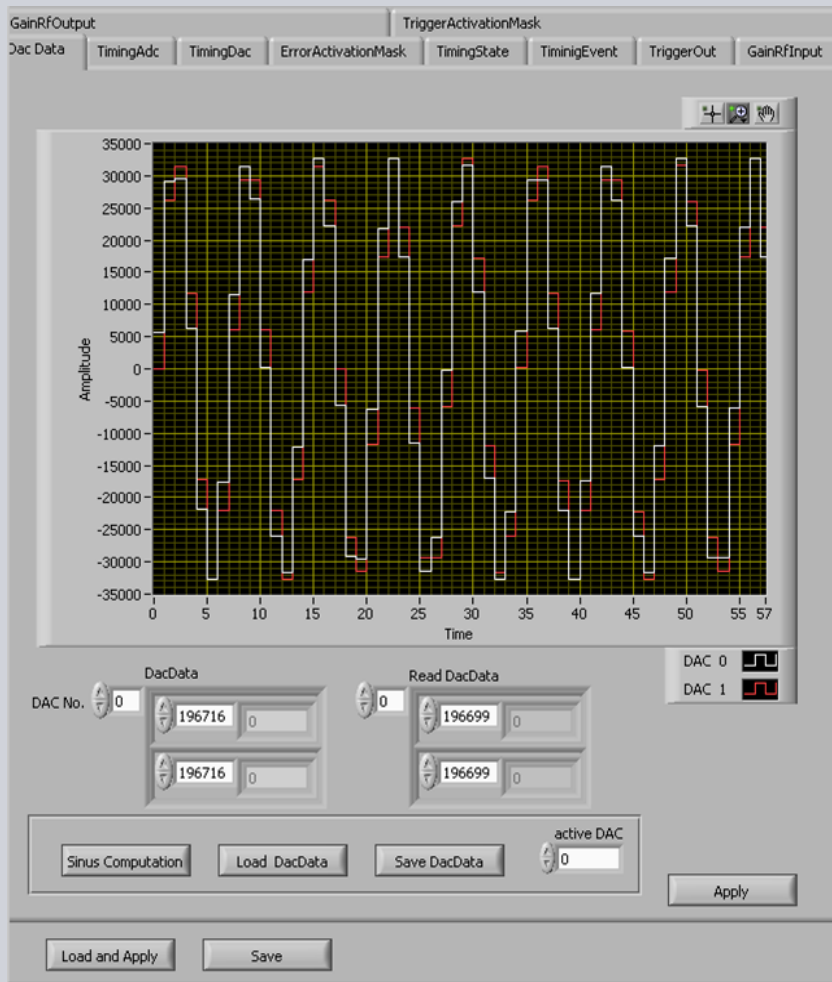
SCCRT first revision

State Machine and LabVIEW Object Oriented Driver



SCCRT first revision

Driver Functionality / LabVIEW Test GUI



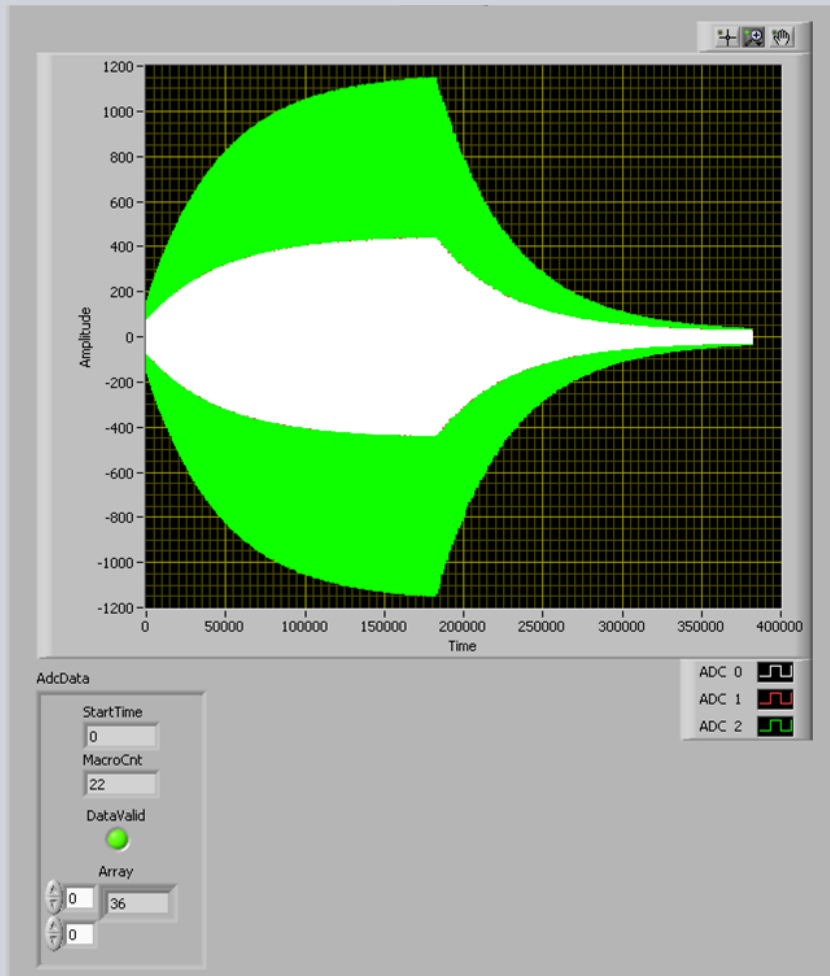
Configuration

The State Machine Control panel includes two columns of controls for CompleteState (auto) and CompleteState (manual). It features a Missing section with a list of components to be applied, each with a red indicator light. At the bottom are buttons for Check, Load, Start, Cancel, Reset Time, GetState, and ResetEventLog.

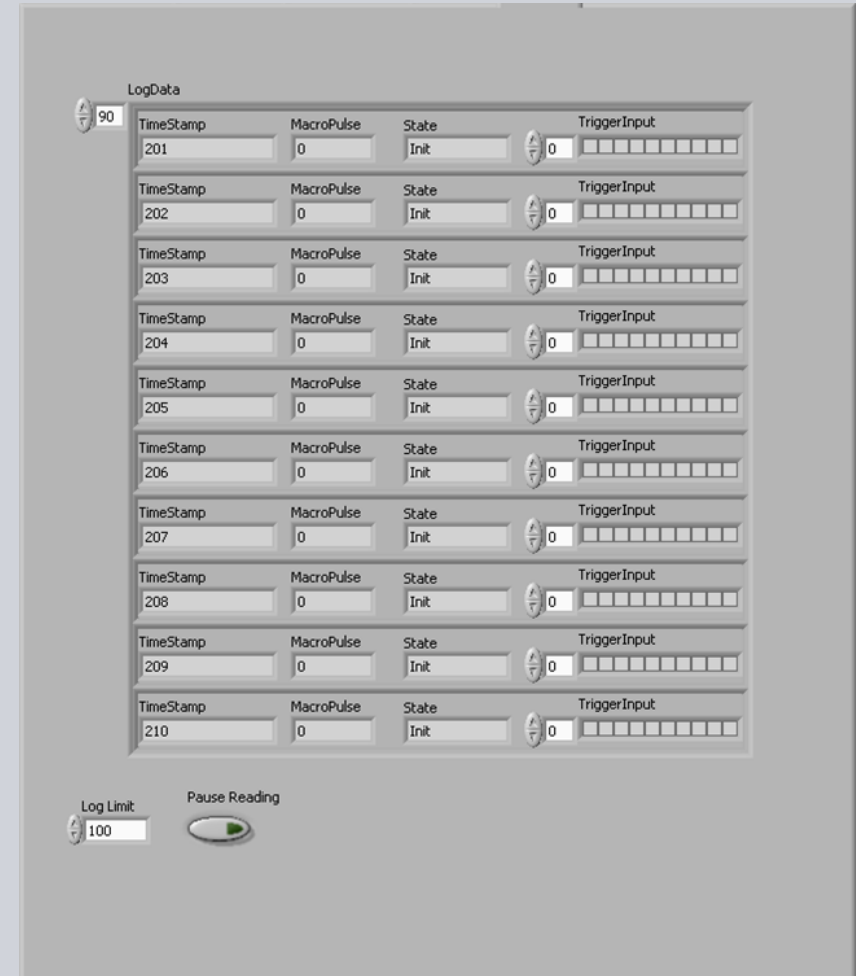
State Machine Control

SCCRT first revision

Driver Functionality and LabVIEW Test GUI

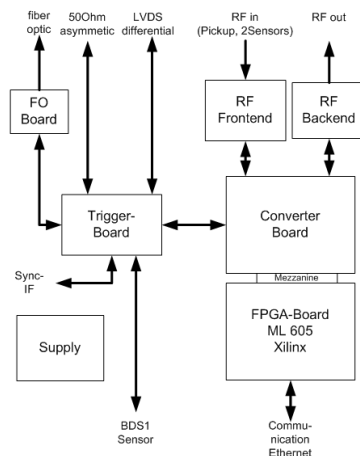
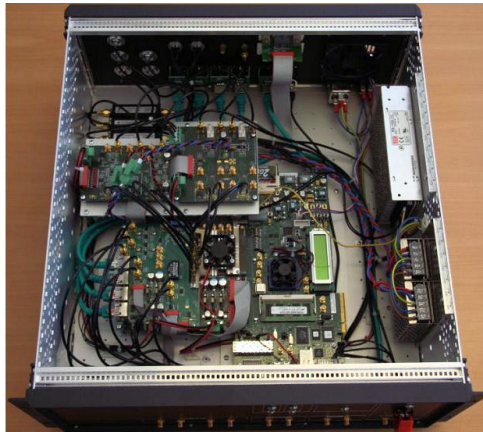


Asynchronous ADC data retrieval (test data by SCCRTUT)

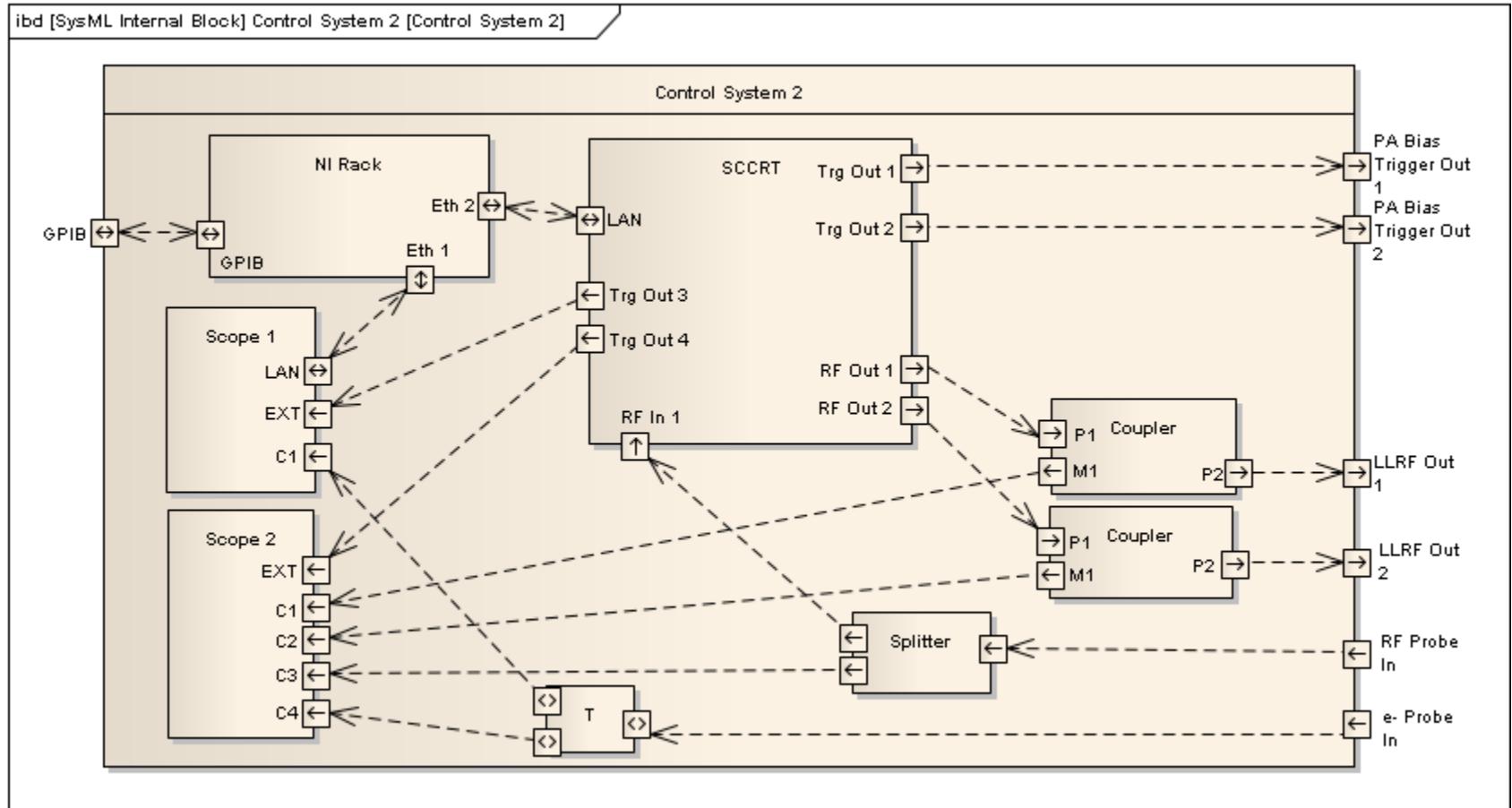


Asynchronous log data retrieval

SCCRT first revision Board Layout and Device Photos



Control (Sub-)System with SCCRT



Results

System commissioning tests:

- 64 modules and 512 SiC Transistors
- control system for power injection tests
- 150MHz
- $U_{DS} = 160V$
- Cavity GAP E-Field approx. 66MV/m
- Transmitted power approx. 120kW

SCCRT first revision:

- Hardware assembled
- LabVIEW driver and unit test code written
- Unit tests just started

Summary & Next Steps

- 64 Modules successfully integrated with control system
- First revision of SCCRT designed and built
- Taking SCCRT into operation has been started

- Next steps:
 - Digital control system:
 - Integration
 - Test outphasing approach
 - System identification
 - Reprogram FPGA (closed loop with PI regulator)
 - Power injection tests with higher module supply voltages



Thank you for your attention!

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